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IPS Rec'd PCT/PTO 26 JUL 2006

**PATENT APPLICATION**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Docket No: Q96164

Katsuhiro TAKENAGA, et al.

Appln. No.: Not yet assigned

Group Art Unit: Not yet assigned

Confirmation No.: Not yet assigned

Examiner: Not yet assigned

Filed: July 26, 2006

For: METHOD FOR MEASURING MULTIMODE OPTICAL FIBER

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 C.F.R. §§ 1.97 and 1.98**

**MAIL STOP AMENDMENT**

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure under 37 C.F.R. § 1.56, Applicant hereby notifies the U.S. Patent and Trademark Office of the documents which are listed on the attached PTO/SB/08 A & B (modified) form and listed herein and which the Examiner may deem material to patentability of the claims of the above-identified application.

1. Japanese Unexamined Patent Application Publication No. 2003-195085, published July 9, 2003 (corresponds with U.S. Patent Publication No. 2003/128942).
2. Shin-Etsu Quartz Products Co., Ltd., Quartz Glass Technical Guide - 1 Chemical and Physical Properties of Quartz Glass, p. 7.  
<http://www.sqp.co.jp/seihin/catalog/pdf/g1.pdf>

INFORMATION DISCLOSURE STATEMENT  
U.S. National Stage Entry of PCT/JP2005/001007

3. Shin-Etsu Quartz Products Co., Ltd., Quartz Glass Technical Guide - 2 Optical Properties of Quartz Glass, p. 7. (<http://www.sqp.co.jp/seihin/catalog/pdf/g2.pdf>)
4. IEC PAS 60793-1-49: "Optical fibres - Part 1-49: Measurement methods and test procedures 0 Differential Mode Delay", May, 2005.
5. Japanese Patent Publication No. 60-214235, published October 26, 1985.
6. Japanese Patent Publication No. 5-248996, published September 28, 1993.

One copy of each of the listed documents is submitted herewith, except for the following: U.S. patents and/or U.S. patent publications; and co-pending non-provisional U.S. applications filed after June 30, 2003.

The present Information Disclosure Statement is being filed: (1) No later than three months from the application's filing date; (2) Before the mailing date of the first Office Action on the merits (whichever is later); or (3) Before the mailing date of the first Office Action after filing a request for continued examination (RCE) under §1.114, and therefore, no Statement under 37 C.F.R. § 1.97(e) or fee under 37 C.F.R. § 1.17(p) is required.

In compliance with the concise explanation requirement under 37 C.F.R. § 1.98(a)(3) for foreign language documents, Applicant states that references 1 - 3 are cited within the specification and references 4 - 6 are cited on the enclosed International Search Report issued in the corresponding International Application.

The submission of the listed documents is not intended as an admission that any such document constitutes prior art against the claims of the present application. Applicant does not waive any right to take any action that would be appropriate to antedate or otherwise remove any listed document as a competent reference against the claims of the present application.

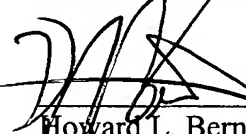
10/587303

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U.S. National Stage Entry of PCT/JP2005/001007

10/587303 26 JUL 2006

The USPTO is directed and authorized to charge all required fees, except for the Issue Fee and the Publication Fee, to Deposit Account No. 19-4880. Please also credit any overpayments to said Deposit Account.

Respectfully submitted,

  
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WASHINGTON OFFICE

23373

CUSTOMER NUMBER

Date: July 26, 2006

Substitute for Form 1449 A &amp; B/PTO

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Complete if Known

Application Number	Not yet assigned
Confirmation Number	Not yet assigned
Filing Date	July 26, 2006
First Named Inventor	Katsuhiro TAKENAGA
Art Unit	Not yet assigned
Examiner Name	Not yet assigned
Attorney Docket Number	Q96164

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of

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**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>2</sup> (if known)		
		US 2003/128942	A	07-10-2003	DiGiovanni et al.
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)			
		JP	60-214235	A	10-26-1985	Hitachi Cable, Ltd.	
		JP	5-248996	A	09-28-1993	Nippon Telegraph and Telephone Corp.	
		JP	2003-195085	A	07-09-2003	Fitel USA Corp	

**NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation <sup>6</sup>
		IEC PAS 60793-1-49: "Optical fibres - Part 1-49: Measurement methods and test procedures 0 Differential Mode Delay", May, 2005.	
		Shin-Etsu Quartz Products Co., Ltd., Quartz Glass Technical Guide - 2 Optical Properties of Quartz Glass, p. 7. ( <a href="http://www.sqp.co.jp/seihin/catalog/pdf/g2.pdf">http://www.sqp.co.jp/seihin/catalog/pdf/g2.pdf</a> )	
		Shin-Etsu Quartz Products Co., Ltd., Quartz Glass Technical Guide - 1 Chemical and Physical Properties of Quartz Glass, p. 7. <a href="http://www.sqp.co.jp/seihin/catalog/pdf/g1.pdf">http://www.sqp.co.jp/seihin/catalog/pdf/g1.pdf</a>	

Examiner Signature

Date Considered

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kind Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov), MPEP 901.04 or follow the hyperlink from the title of the document to the intranet. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to indicate here if English language Translation is attached.